

IEEE International Conference on Metrology for eXtended Reality, Artificial Intelligence and Neural Engineering

DATE: Thursday, October 23, 2025
LOCATION: Ancona, Marche, IT

Event Description

IEEE International Conference on Metrology for eXtended Reality, Artificial Intelligence and Neural Engineering is a premier conferences event in Ancona. This event attracts visitors from around the world and significantly impacts local hotel demand, creating opportunities for strategic revenue management and guest experience optimization.

Key Information

Category: conferences

Importance Rank: 44/100

Expected Attendance: 500 people

Event ID: 3Qeq7pUHWth3Dtgytq

Hotel Demand Indicators

ADR Impact Index: 5.2x baseline (varies by property tier & location)

Occupancy Impact: +60 percentage points over baseline

Booking Lead Time: Demand begins 30 days before event

Impact Radius: 15km from venue

Estimated Room Nights: 200 across all properties

Note: Actual impact varies by property location, star rating, and local market conditions.